

FORM PTO 1449 (modified) U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE LIST OF REFERENCES CITED BY APPLICANT(S) (Use several sheets if necessary) Date Submitted to PTO: [DATE]				ATTY DOCKET NO. 03500.017320.		APPLICATION NO. 10/516,545	
				APPLICANTS TAKESHI ICHIKAWA ET AL.			
				FILING DATE DECEMBER 2, 2004		GROUP 2879	

U.S. PATENT DOCUMENTS							
*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
R		2002-057045	05/16/02	Tsukamoto	313	309	

FOREIGN PATENT DOCUMENTS							
	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT	
R	EPA	1056110	11/29/00	EPO	H01J	1/30	
R		03/046255	06/05/03	WIPO	C23C	16/56	
R		99/028939	06/10/99	WIPO	H01J	1/30	

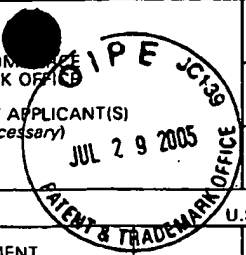
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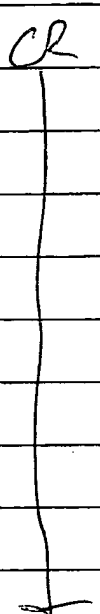
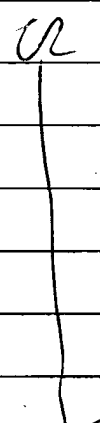
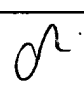
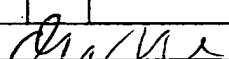
EXAMINER	DATE CONSIDERED <u>1/21/07</u>
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	4,663,559	5/87	Christensen	313	336		
	5,939,823	8/99	Kiyomiya et al.	313	495		
	5,989,404	11/99	Kiyomiya et al.	205	96		
	6,288,494	9/01	Tsukamoto et al.	315	169.1		
	6,583,582	6/03	Ichikawa	315	169.3		
	6,583,553	6/03	Sasaguri	313	495		
	6,650,061	11/03	Urayama et al.	315	169.3		
	6,683,408	1/04	Ichikawa	313	495		
	2004/0251812 A1	12/04	Fujiwara et al.	313	495		
		6,861,790	3/05	Iwasa et al.	313	346	
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	8-96703	4/96	Japan			Abstract	
	2001-6523	1/01	Japan			Abstract	
	2001-101966	4/01	Japan			Abstract	
	4-131846	5/92	Japan			Abstract	
	8-96704	4/96	Japan			Abstract	
	8-264109	10/96	Japan			Abstract	
	2001-202870	7/01	Japan			Abstract	
OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)							
	Forest, R.D., et al., <i>A Study of Electron Field Emission as a function of film thickness from amorphous Carbon Films</i> , Applied Physics Letters, Vol. 73, No. 25, pp 3784-3786 (1998)						
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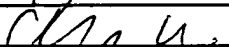
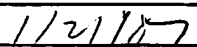
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OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)	
	Ding, Xing-zhao, et al. <i>Electron Field Emission from Ti-containing Tetrahedral Amorphous Carbon Films Deposited by Filtered Cathodic Vacuum Arc</i> , Journal of Applied Physics, Volume 88, No. 11, pp. 6842-6847 (2000)
	Li, Y.J., et al., <i>Field Emission from Cobalt-containing Amorphous Carbon Composite Films Heat-treated in an Acetylene Ambient</i> , Applied Physics Letters, Volume 77, No. 13, pp. 2021-2023 (2000)
	Forbes, Richard G., <i>Low-macroscopic-field Electron Emission from Carbon Films and other Electrically Nanostructured Heterogeneous Materials: Hypotheses about Emission Mechanism</i> , Solid-State Electronics 45 pp. 779-808 (2001)
	Lau, S.P., et al., <i>Field Emission from Metal-containing Amorphous Carbon Composite Films, Diamond and Related Materials</i> 10, pp. 1727-1731 (2001)
	Bajic, S., et al., <i>Enhanced Cold-cathode Emission Using Composite Resin-Carbon Coatings</i> , J. Phys., D: Appl. Phys. 21, pp. 200-204)
	Burden, A.P., et al., <i>Field Emitting Inks for Consumer-priced Broad-area Flat-panel Displays</i> , J. Vac. Sci, Technol. B 18(w), pp. 900-904 (1999)

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10/516545

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		S.P. Lau et al., "Field Emission from Metal-Containing Amorphous Carbon Composite Films", Diamond and Related Materials, Vol. 10 (2001); pp. 1727-1731.					
		Richard G. Forbes, "Low-Macroscopic-Field Electron Emission From Carbon Films and Other Electrically Nanostructured Heterogeneous Materials: Hypotheses About Emission Mechanism", Solid State Electronics, Vol. 45 (2001); pp. 779-808.					
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